



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

FIME KOREA LTD.
Sewoong Tower 12F, 12, Seolleung-ro94-gil, Gangnam-gu
Seoul, 06162, South Korea
Representative: Cecilia Lee, +82 (0)2 2051 0428
cecilia.lee@fime.com

ELECTRICAL

Valid To: May 31, 2022

Certificate Number: 3563.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following Electrical tests:

Tests:

Proximity Integrated Circuit Card (PICC)
L1 Testing
(Analogue and Digital)

Mobile Product L1 Testing
(Analogue, Digital, Performance,
and Interoperability)

NFC Forum Testing

Test Methods:

EMVCo Contactless Specifications for Payment
Systems Book D, using:
- EMVCo Contactless Type Approval PICC Analogue
Test Bench and Test Case Requirements
- EMVCo PICC Level 1 Protocol Digital Test Cases

EMVCo Contactless Specifications for Payment
Systems Book D, using:
- EMVCo Contactless Type Approval PICC
Analogue Test Bench and Test Case Requirements
- EMVCo PICC Level 1 Protocol Digital Test Cases
- EMVCo Mobile L1 Performance Test Cases
- EMVCo Mobile Product Interoperability Testing
Requirements

NFC Forum Analog Technical Specification,
using NFC Forum Test Cases for RF Analog;

NFC Forum Digital Protocol Technical
Specification, using NFC Forum Test Cases for
Digital Protocol;

NFC Forum LLCP Technical Specification,
using NFC Forum Test Cases for LLCP;

NFC Forum SNEP Technical Specification,
using NFC Forum Test Cases For SNEP;

Tests:

NFC Forum Testing
(Cont'd)

Global Certification Forum Testing

Proximity Coupling Device (PCD) L1 Testing
(Analogue, Digital and Pre-Validation)

Test Methods:

NFC Forum Type1 Tag Technical Specification,
using NFC Forum Test Cases for Type1 Tag;

NFC Forum Type2 Tag Technical Specification,
using NFC Forum Test Cases for Type2 Tag;

NFC Forum Type3 Tag Technical Specification,
using NFC Forum Test Cases for Type3 Tag;

NFC Forum Type4 Tag Technical Specification,
using NFC Forum Test Cases for Type4 Tag

GSMA TS.27 NFC Handset Test Book;

ETSI Smart Cards, Test specification for the Single
Wire Protocol (SWP) Interface, Part 1: Terminal
Features (ETSI TS 102 694-01);

ETSI Smart Cards, Test specification for the Host
Controller Interface (HCI), Part 1: Terminal
Features (ETSI TS 102 695-01)

EMVCo Contactless Specifications for Payment
Systems Book D, using:

- EMVCo Contactless Type Approval PCD Analogue
Test Bench and Test Case Requirements
- EMVCo Contactless Type Approval PCD
Digital Test Bench and Test Cases
- EMVCo Contactless Type Approval PCD
Pre-Validation Test

On the following products or types of products:

NFC Capable devices, Card Emulation Mode, Read/Writer Mode and Peer to Peer Mode



Accredited Laboratory

A2LA has accredited

FIME KOREA LTD.

Seoul, South Korea

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 19th day of October 2020.

A blue ink signature of the Vice President, Accreditation Services.

Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 3563.01
Valid to May 31, 2022

For the tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.